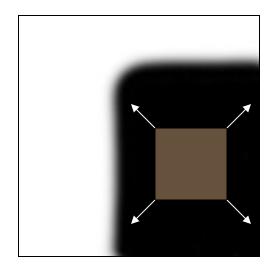
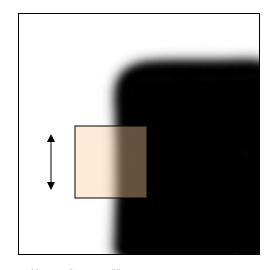
Correspondence

Corner Detection: Basic Idea

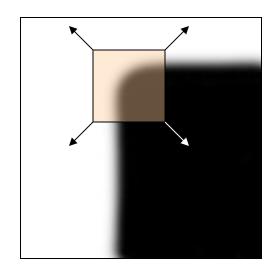
- We should easily recognize the point by looking through a small window
- Shifting a window in *any direction* should give *a large change* in intensity



"flat" region: no change in all directions



"edge":
no change
along the edge
direction



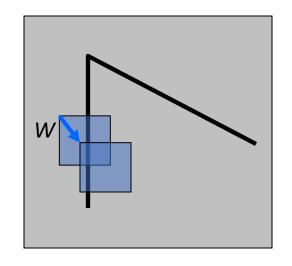
"corner":
significant
change in all
directions

Source: A. Efros

Corner detection: the math

Consider shifting the window W by (u,v)

- how do the pixels in W change?
- compare each pixel before and after by summing up the squared differences (SSD)
- this defines an SSD "error" E(u,v):



$$E(u,v) = \sum_{(x,y)\in W} [I(x+u,y+v) - I(x,y)]^2$$

 We want E(u,v) to be as high as possible for all u, v!

Small motion assumption

Taylor Series expansion of *I*:

$$I(x+u,y+v) = I(x,y) + \frac{\partial I}{\partial x}u + \frac{\partial I}{\partial y}v + \text{higher order terms}$$

If the motion (u,v) is small, then first order approximation is good

$$I(x+u,y+v) \approx I(x,y) + \frac{\partial I}{\partial x}u + \frac{\partial I}{\partial y}v$$
$$\approx I(x,y) + [I_x \ I_y] \begin{bmatrix} u \\ v \end{bmatrix}$$

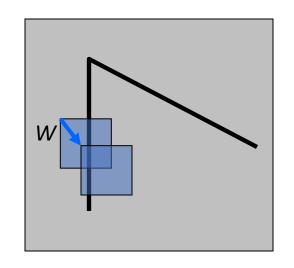
shorthand: $I_x = \frac{\partial I}{\partial x}$

Plugging this into the formula on the previous slide...

Corner detection: the math

Consider shifting the window W by (u,v)

• define an SSD "error" *E(u,v)*:



$$E(u,v) = \sum_{(x,y)\in W} [I(x+u,y+v) - I(x,y)]^{2}$$

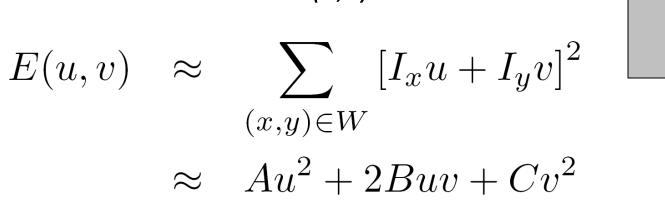
$$\approx \sum_{(x,y)\in W} [I(x,y) + I_{x}u + I_{y}v - I(x,y)]^{2}$$

$$\approx \sum_{(x,y)\in W} [I_{x}u + I_{y}v]^{2}$$

Corner detection: the math

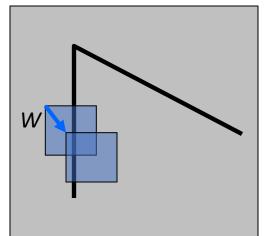
Consider shifting the window W by (u,v)

• define an "error" *E(u,v)*:



$$A = \sum_{(x,y)\in W} I_x^2 \qquad B = \sum_{(x,y)\in W} I_x I_y \qquad C = \sum_{(x,y)\in W} I_y^2$$

• Thus, E(u,v) is locally approximated as a quadratic error function



Interpreting the second moment matrix

Recall that we want E(u,v) to be as large as possible for all u,v

What does this mean in terms of M?

$$E(u,v) \approx [u \ v] M \begin{bmatrix} u \\ v \end{bmatrix}$$

$$M = \sum_{x,y} w(x,y) \begin{bmatrix} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{bmatrix}$$

Second moment matrix

$$E(u,v) \approx \left[\begin{array}{ccc} u & v \end{array} \right] M \left[\begin{array}{ccc} u \\ v \end{array} \right]$$

$$M \begin{bmatrix} u \\ v \end{bmatrix} = \begin{bmatrix} 0 \\ 0 \end{bmatrix} \Rightarrow E(u, v) = 0$$

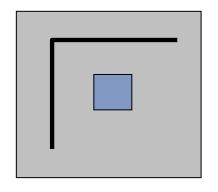
$$M \left[\begin{array}{c} u \\ v \end{array} \right] = \left[\begin{array}{c} 0 \\ 0 \end{array} \right] \Leftrightarrow E(u, v) = 0$$

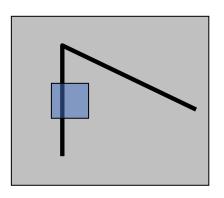
Solutions to Mx = 0 are directions for which E is 0: window can slide in this direction without changing appearance

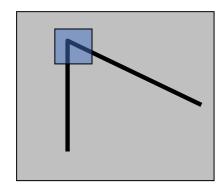
$$E(u,v) \approx \left[\begin{array}{cc|c} u & v \end{array} \right] M \left[\begin{array}{cc|c} u \\ v \end{array} \right]$$

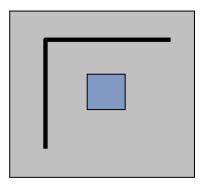
Solutions to Mx = 0 are directions for which E is 0: window can slide in this direction without changing appearance

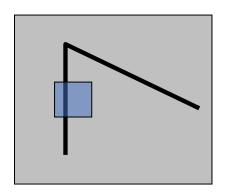
For corners, we want no such directions to exist

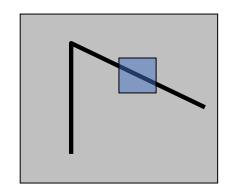


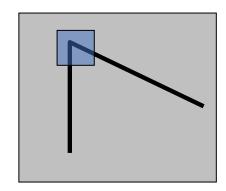


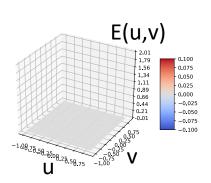


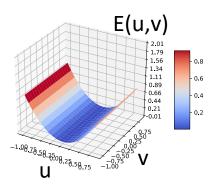


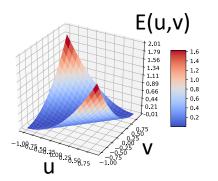


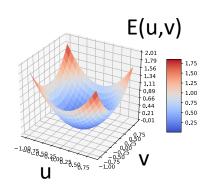










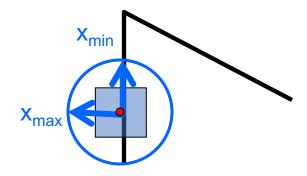


Eigenvalues and eigenvectors of M

- $Mx = 0 \Rightarrow Mx = \lambda x$: x is an eigenvector of M with eigenvalue 0
- M is 2 x 2, so it has 2 eigenvalues $(\lambda_{max}, \lambda_{min})$ with eigenvectors (x_{max}, x_{min})
- $E(x_{max}) = x_{max}^T M x_{max} = \lambda_{max} ||x_{max}||^2 = \lambda_{max}$ (eigenvectors have unit norm)
- $E(x_{min}) = x_{min}^T M x_{min} = \lambda_{min} ||x_{min}||^2 = \lambda_{min}$

Eigenvalues and eigenvectors of M

$$E(u,v) \approx \left[\begin{array}{ccc|c} u & v \end{array} \right] M \left[\begin{array}{ccc|c} u \\ v \end{array} \right]$$



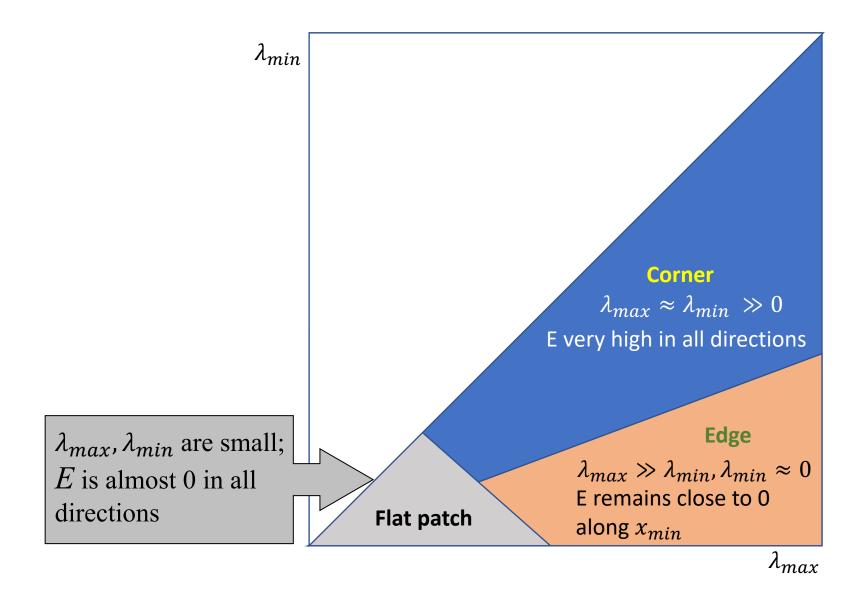
M
$$x_{\max} = \lambda_{\max} x_{\max}$$

$$M x_{\min} = \lambda_{\min} x_{\min}$$

Eigenvalues and eigenvectors of M

- Define shift directions with the smallest and largest change in error
- x_{max} = direction of largest increase in E
- λ_{max} = amount of increase in direction x_{max}
- x_{min} = direction of smallest increase in E
- λ_{min} = amount of increase in direction x_{min}

Interpreting the eigenvalues



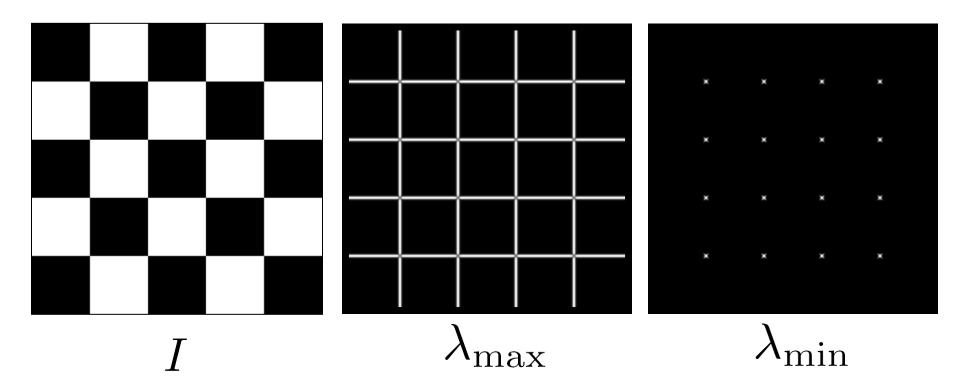
Corner detection: the math

How are λ_{max} , x_{max} , λ_{min} , and x_{min} relevant for feature detection?

Need a feature scoring function

Want E(u,v) to be large for small shifts in all directions

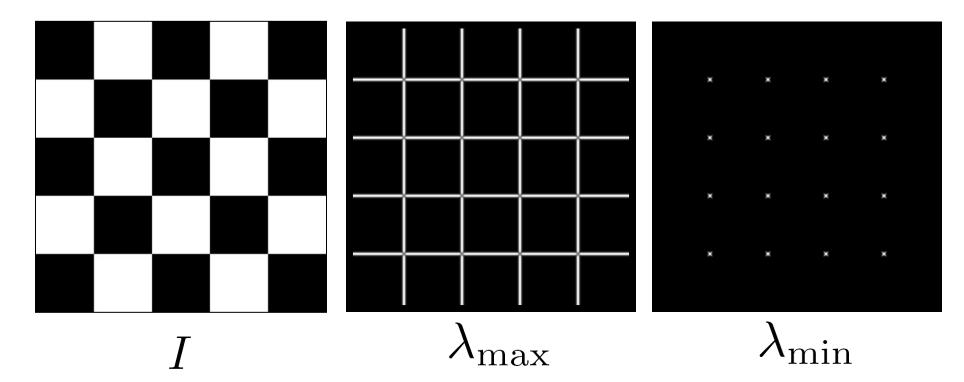
- the minimum of E(u,v) should be large, over all unit vectors $[u \ v]$
- this minimum is given by the smaller eigenvalue (λ_{min}) of M



Corner detection summary

Here's what you do

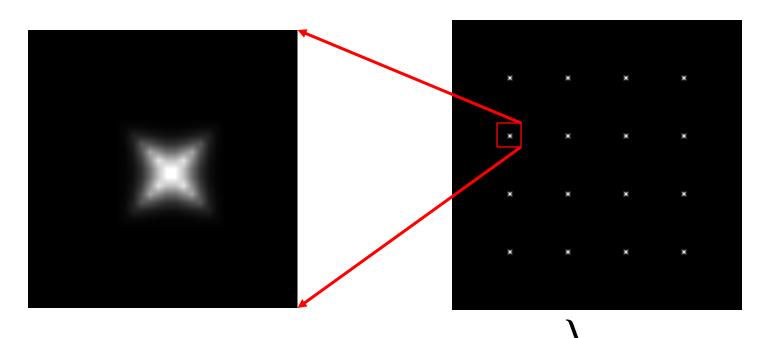
- Compute the gradient at each point in the image
- Create the *M* matrix from the entries in the gradient
- Compute the eigenvalues
- Find points with large response (λ_{min} > threshold)
- Choose those points where λ_{min} is a local maximum as features



Corner detection summary

Here's what you do

- Compute the gradient at each point in the image
- Create the *H* matrix from the entries in the gradient
- Compute the eigenvalues.
- Find points with large response (λ_{min} > threshold)
- Choose those points where λ_{min} is a local maximum as features



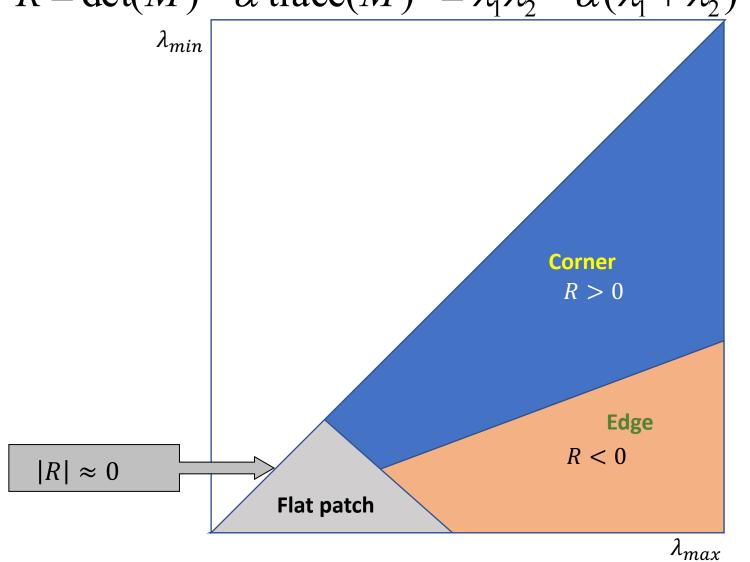
The Harris operator

 λ_{min} is a variant of the "Harris operator" for feature detection

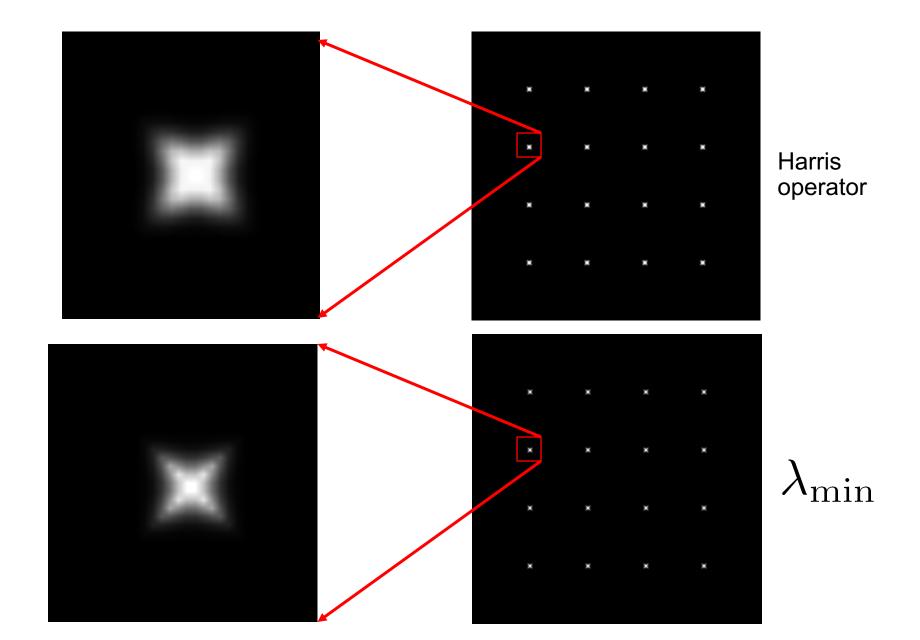
$$f = \frac{\lambda_1 \lambda_2}{\lambda_1 + \lambda_2}$$
$$= \frac{determinant(H)}{trace(H)}$$

- The *trace* is the sum of the diagonals, i.e., $trace(H) = h_{11} + h_{22}$
- Very similar to λ_{min} but less expensive (no square root)
- Called the "Harris Corner Detector" or "Harris Operator"
 - Actually the Noble variant of the Harris Corner Detector
- Lots of other detectors, this is one of the most popular

Corner response function $R = \det(M) - \alpha \operatorname{trace}(M)^{2} = \lambda_{1}\lambda_{2} - \alpha(\lambda_{1} + \lambda_{2})^{2}$

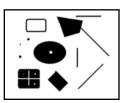


The Harris operator



Harris Detector [Harris88]

Second moment matrix



$$\mu(\sigma_{I}, \sigma_{D}) = g(\sigma_{I}) * \begin{bmatrix} I_{x}^{2}(\sigma_{D}) & I_{x}I_{y}(\sigma_{D}) \\ I_{x}I_{y}(\sigma_{D}) & I_{y}^{2}(\sigma_{D}) \end{bmatrix}$$
 1. Image derivatives (optionally, blur first)



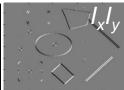


$$\det M = \lambda_1 \lambda_2$$
$$\operatorname{trace} M = \lambda_1 + \lambda_2$$

2. Square of derivatives



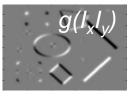




3. Gaussian filter $g(\sigma_l)$







4. Cornerness function – both eigenvalues are strong

$$har = \det[\mu(\sigma_{I}, \sigma_{D})] - \alpha[\operatorname{trace}(\mu(\sigma_{I}, \sigma_{D}))^{2}] =$$

$$g(I_{x}^{2})g(I_{y}^{2}) - [g(I_{x}I_{y})]^{2} - \alpha[g(I_{x}^{2}) + g(I_{y}^{2})]^{2}$$

5. Non-maxima suppression



Weighting the derivatives

• In practice, using a simple window W doesn't work too well

$$H = \sum_{(x,y) \in W} \left[\begin{array}{cc} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{array} \right] \text{d on its distance from}$$

the center pixel

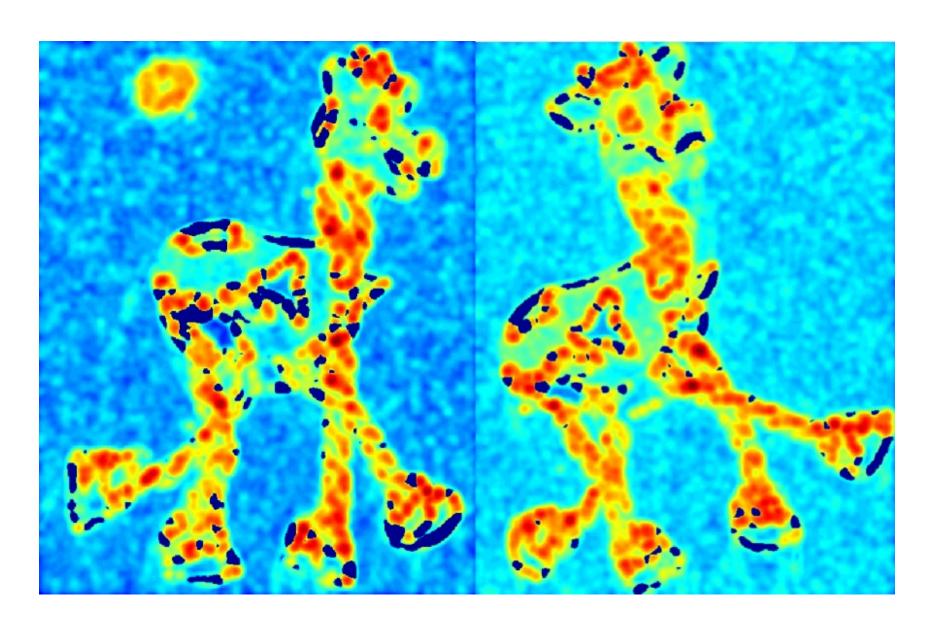
$$H = \sum_{(x,y)\in W} w_{x,y} \begin{bmatrix} I_x^2 & I_x I_y \\ I_x I_y & I_y^2 \end{bmatrix}$$



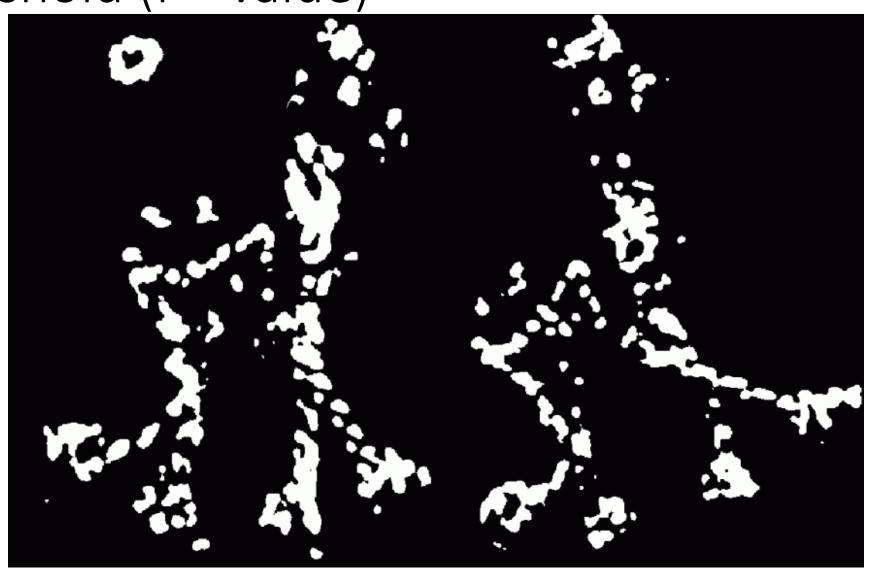
Harris detector example



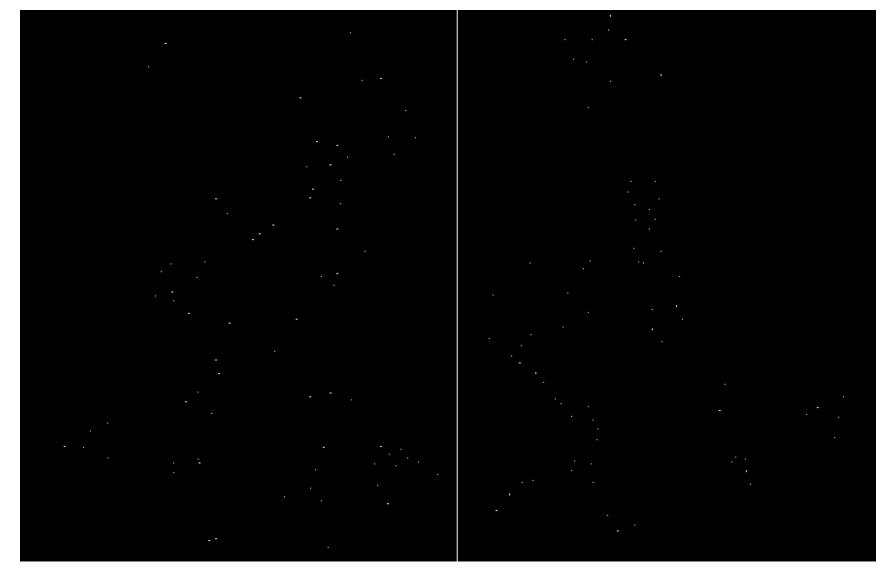
f value (red high, blue low)



Threshold (f > value)



Find local maxima of f

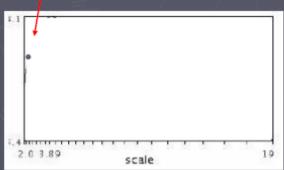


Harris features (in red)



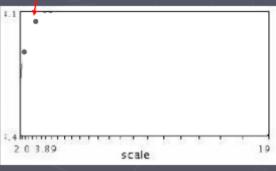
Lindeberg et al., 1996





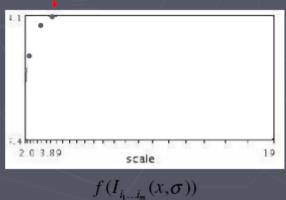
$$f(I_{i_1...i_m}(x,\sigma))$$



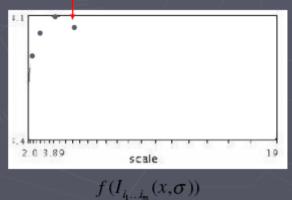


$$f(I_{i_1...i_m}(x,\sigma))$$

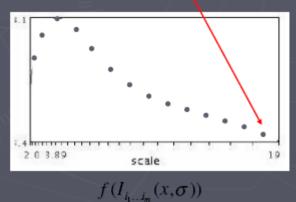




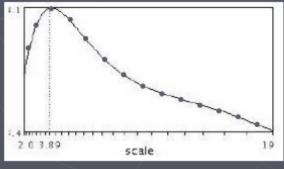












$$f(I_{i_1...i_m}(x,\sigma))$$

Implementation

 Instead of computing f for larger and larger windows, we can implement using a fixed window size with a Gaussian pyramid



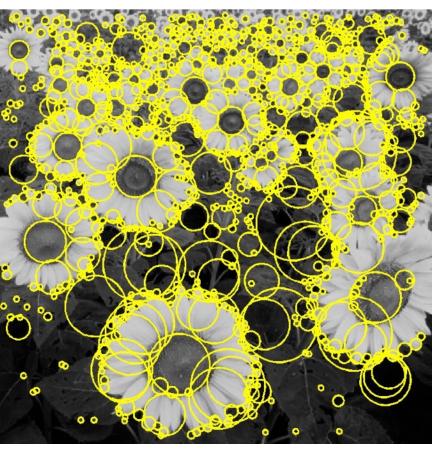






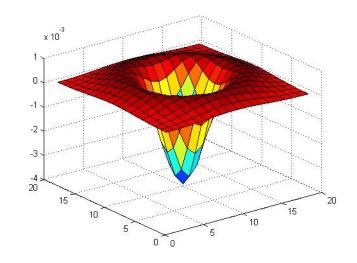
Feature extraction: Corners and blobs

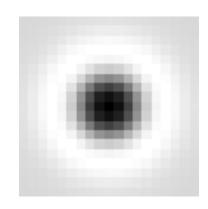




Another common definition of *f*

• The Laplacian of Gaussian (LoG)



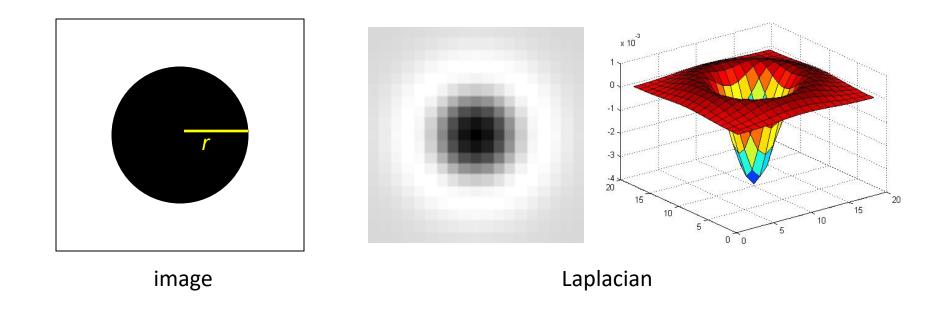


$$\nabla^2 g = \frac{\partial^2 g}{\partial x^2} + \frac{\partial^2 g}{\partial y^2}$$

(very similar to a Difference of Gaussians (DoG) – i.e. a Gaussian minus a slightly smaller Gaussian)

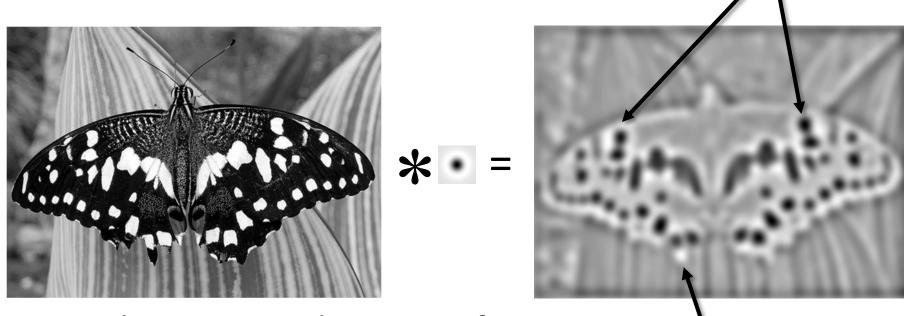
Scale selection

• At what scale does the Laplacian achieve a maximum response for a binary circle of radius r?



Laplacian of Gaussian

• "Blob" detector

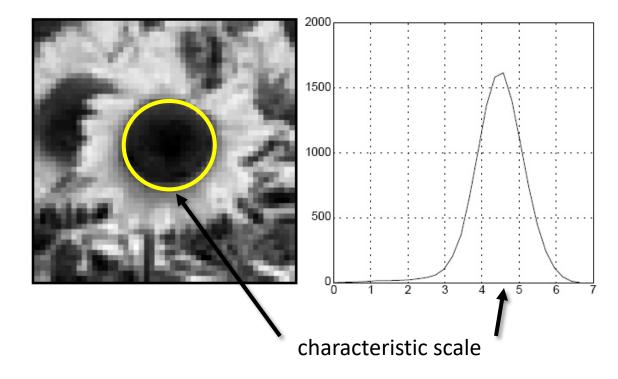


minima

• Find maxima and minima of LoG operatorakm space and scale

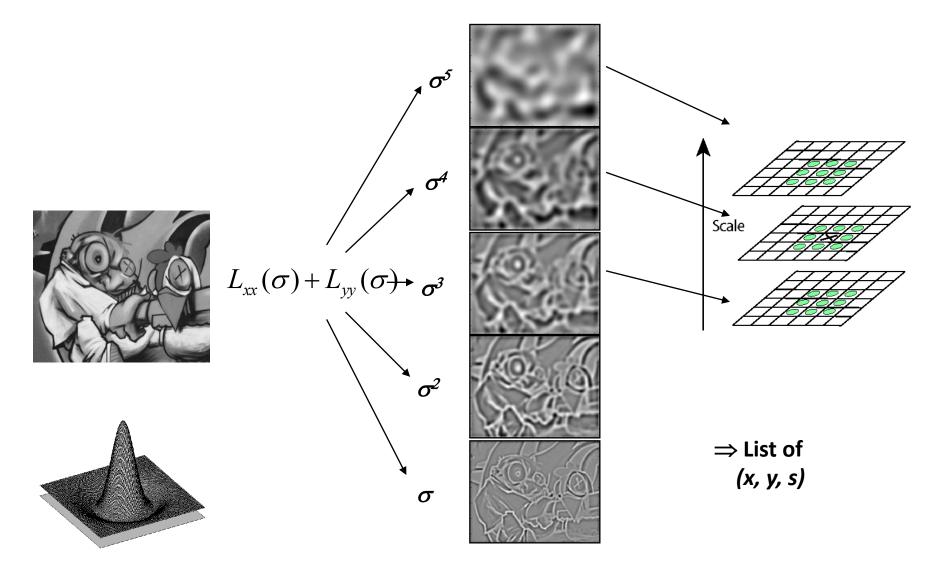
Characteristic scale

• The scale that produces peak of Laplacian response



T. Lindeberg (1998). <u>"Feature detection with automatic scale selection."</u> *International Journal of Computer Vision* **30** (2): pp 77--116.

Find local maxima in position-scale space



Scale-space blob detector: Example

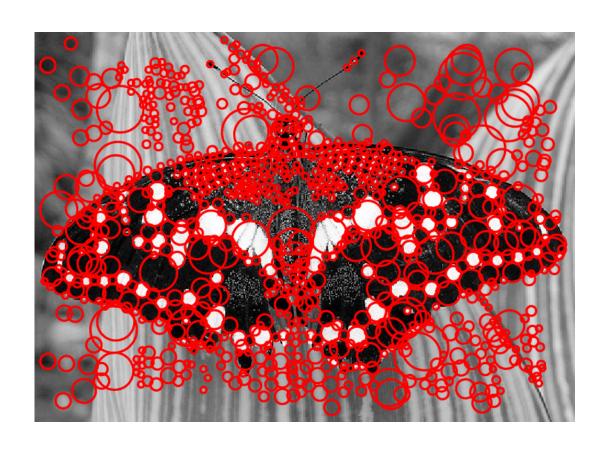


Scale-space blob detector: Example



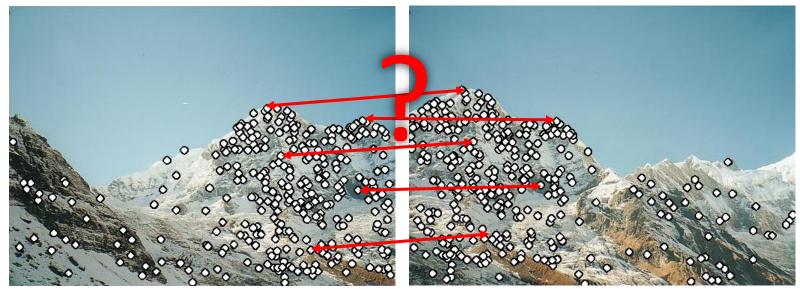
sigma = 11.9912

Scale-space blob detector: Example



Matching feature points

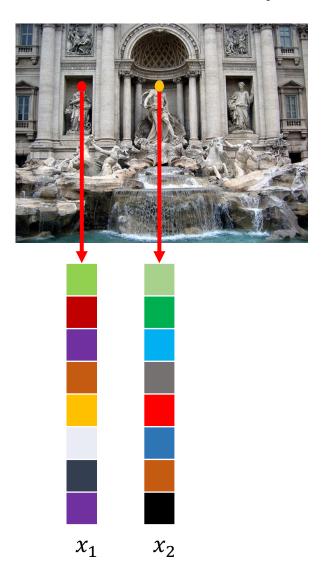
We know how to detect good points Next question: How to match them?

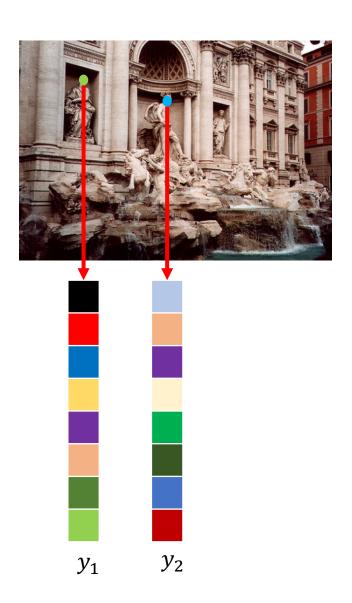


Two interrelated questions:

- 1. How do we *describe* each feature point?
- 2. How do we *match* descriptions?

Feature descriptor





Feature matching

 Measure the distance between (or similarity between) every pair of descriptors

	y_1	y_2
x_1	$d(x_1, y_1)$	$d(x_1, y_2)$
x_2	$d(x_2, y_1)$	$d(x_2, y_2)$

Invariance vs. discriminability

- Invariance:
 - Distance between descriptors should be small even if image is transformed

- Discriminability:
 - Descriptor should be highly unique for each point (far away from other points in the image)

Image transformations

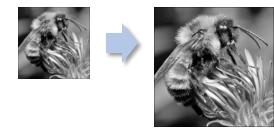
• Geometric

Rotation



Scale











Invariance

- Most feature descriptors are designed to be invariant to
 - Translation, 2D rotation, scale

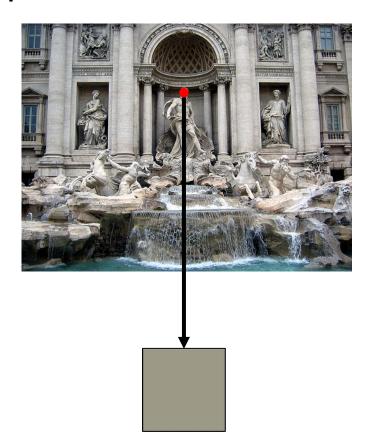
- They can usually also handle
 - Limited 3D rotations (SIFT works up to about 60 degrees)
 - Limited affine transformations (some are fully affine invariant)
 - Limited illumination/contrast changes

How to achieve invariance

Design an invariant feature descriptor

- Simplest descriptor: a single 0
 - What's this invariant to?
 - Is this discriminative?
- Next simplest descriptor: a single pixel
 - What's this invariant to?
 - Is this discriminative?

The aperture problem



The aperture problem

• Use a whole patch instead of a pixel?



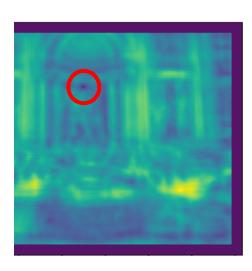
SSD

- Use as descriptor the whole patch
- Match descriptors using euclidean distance

•
$$d(x,y) = ||x - y||^2$$



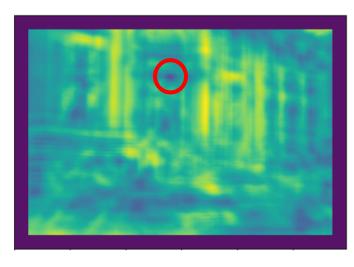




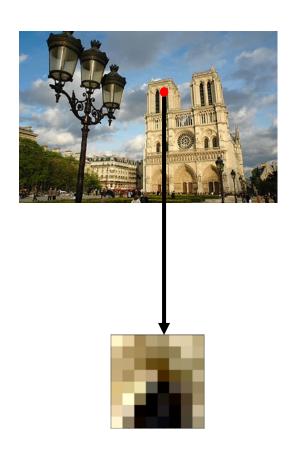
SSD



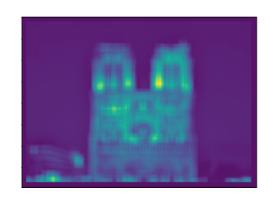




SSD



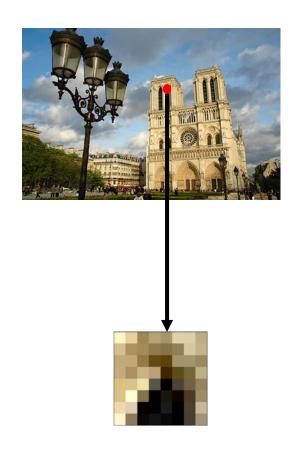




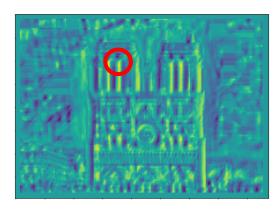
NCC - Normalized Cross Correlation

- Lighting and color change pixel intensities
- Example: increase brightness / contrast
- $I' = \alpha I + \beta$
- Subtract patch mean: invariance to eta
- Divide by norm of vector: invariance to α
- x' = x < x >
- $\bullet \ x'' = \frac{x'}{||x'||}$
- $similarity = x'' \cdot y''$

NCC - Normalized cross correlation







Basic correspondence

- Image patch as descriptor, NCC as similarity
- Invariant to?
 - Photometric transformations?
 - Translation?
 - Rotation?

Rotation invariance for feature descriptors

- Find dominant orientation of the image patch
 - This is given by \mathbf{x}_{max} , the eigenvector of \mathbf{M} corresponding to λ_{max} (the *larger* eigenvalue)
 - Rotate the patch according to this angle

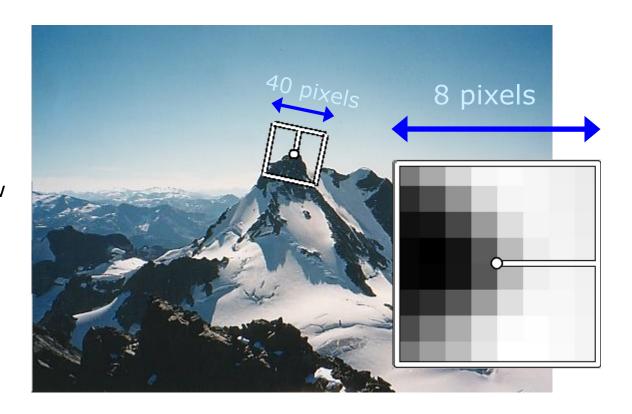


Figure by Matthew Brown

Multiscale Oriented PatcheS descriptor

Take 40x40 square window around detected feature

- Scale to 1/5 size (using prefiltering)
- Rotate to horizontal
- Sample 8x8 square window centered at feature
- Intensity normalize the window by subtracting the mean, dividing by the standard deviation in the window



Detections at multiple scales

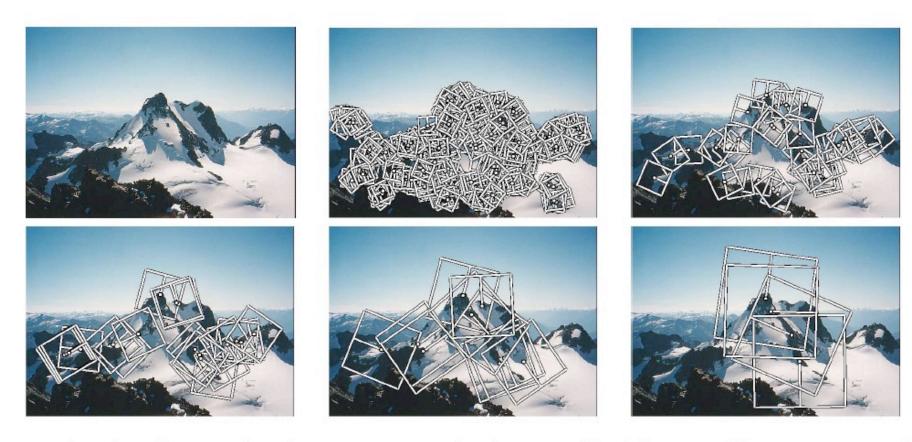


Figure 1. Multi-scale Oriented Patches (MOPS) extracted at five pyramid levels from one of the Matier images. The boxes show the feature orientation and the region from which the descriptor vector is sampled.

Invariance of MOPS

Intensity

Scale

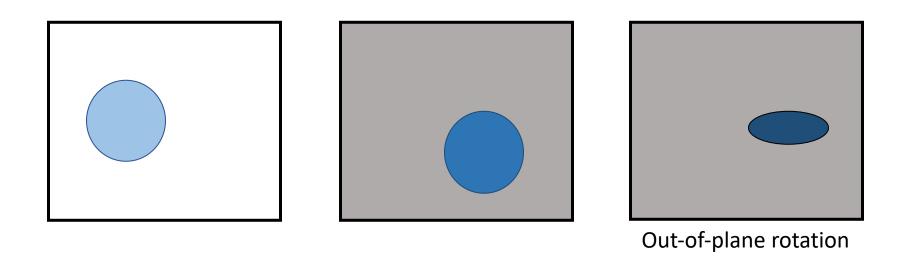
Rotation

Color and Lighting



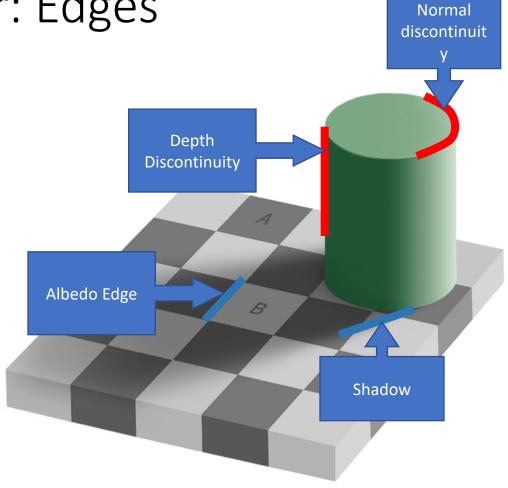


Out-of-plane rotation



Discussion

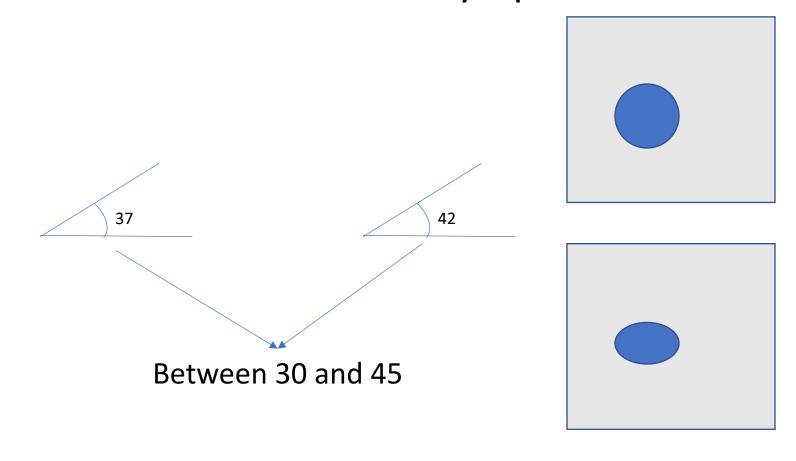
Better representation than color: Edges



Towards a better feature descriptor

- Match pattern of edges
 - Edge orientation clue to shape
- Be resilient to *small deformations*
 - Deformations might move pixels around, but slightly
 - Deformations might change edge orientations, but slightly

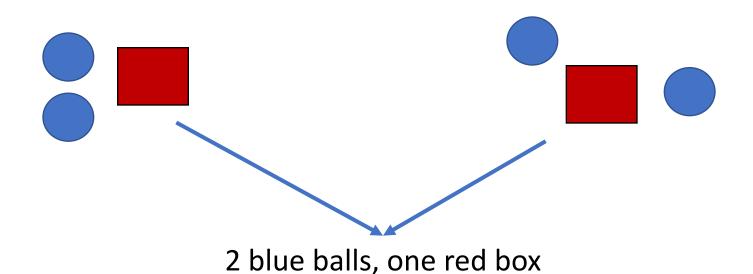
Invariance to deformation by quantization

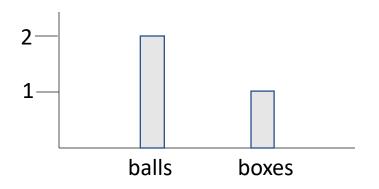


Invariance to deformation by quantization

$$g(\theta) = \begin{cases} 0 & \text{if } 0 < \theta < 2\pi/N \\ 1 & \text{if } 2\pi/N < \theta < 4\pi/N \\ 2 & \text{if } 4\pi/N < \theta < 6\pi/N \\ \dots & \dots \\ N-1 & \text{if } 2(N-1)\pi/N \end{cases}$$

Spatial invariance by histograms

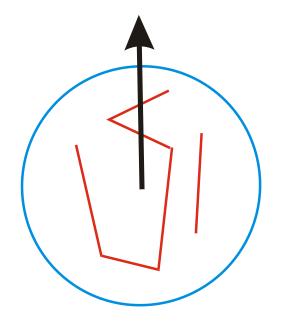


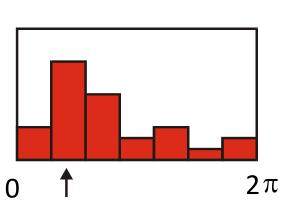


Rotation Invariance by Orientation Normalization

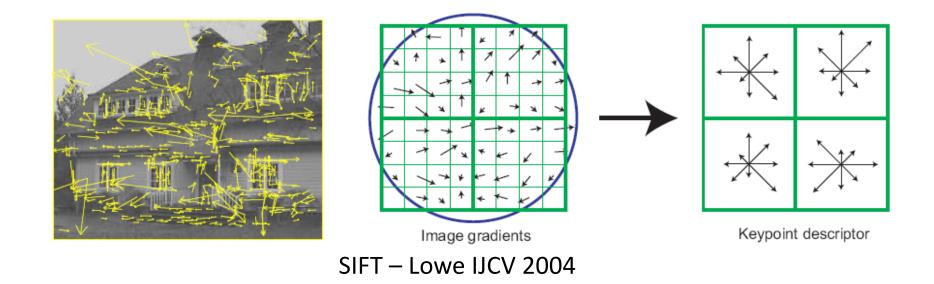
[Lowe, SIFT, 1999]

- Compute orientation histogram
- Select dominant orientation
- Normalize: rotate to fixed orientation





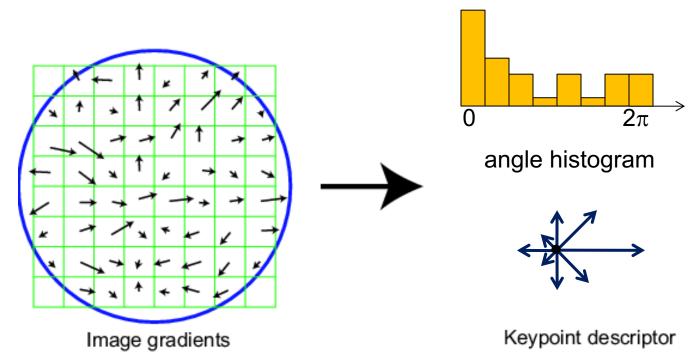
The SIFT descriptor



Scale Invariant Feature Transform

Basic idea:

- DoG for scale-space feature detection
- Take 16x16 square window around detected feature
 - Compute gradient orientation for each pixel
 - Throw out weak edges (threshold gradient magnitude)
 - Create histogram of surviving edge orientations

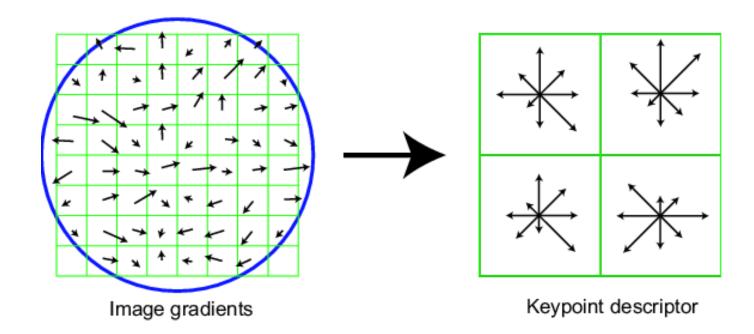


Adapted from slide by David Lowe

SIFT descriptor

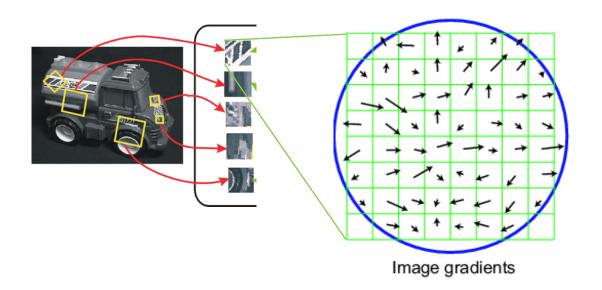
Create histogram

- Divide the 16x16 window into a 4x4 grid of cells (2x2 case shown below)
- Compute an orientation histogram for each cell
- 16 cells * 8 orientations = 128 dimensional descriptor



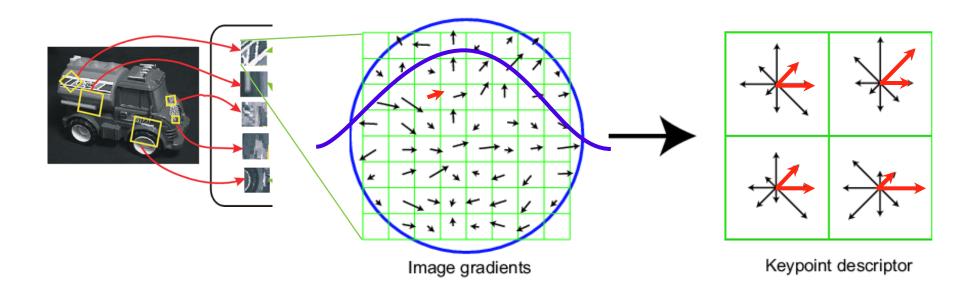
SIFT vector formation

- Computed on rotated and scaled version of window according to computed orientation & scale
 - resample the window
- Based on gradients weighted by a Gaussian



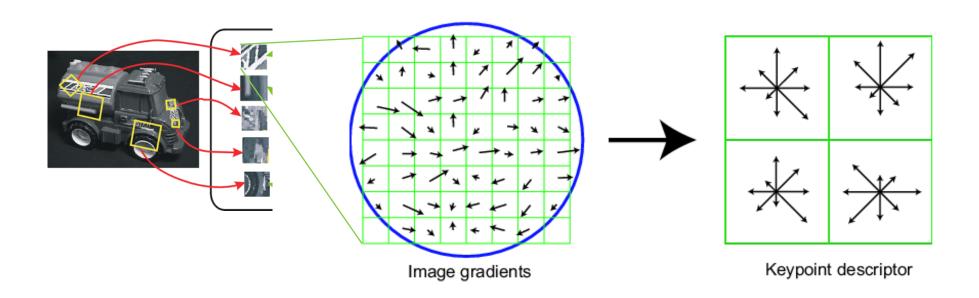
Ensure smoothness

- Trilinear interpolation
 - a given gradient contributes to 8 bins:
 4 in space times 2 in orientation



Reduce effect of illumination

- 128-dim vector normalized to 1
- Threshold gradient magnitudes to avoid excessive influence of high gradients
 - after normalization, clamp gradients >0.2
 - renormalize



Properties of SIFT

Extraordinarily robust matching technique

- Can handle changes in viewpoint
 - Up to about 60 degree out of plane rotation
- Can handle significant changes in illumination
 - Sometimes even day vs. night (below)
- Fast and efficient—can run in real time
- Lots of code available: <u>http://people.csail.mit.edu/albert/ladypack/wiki/index.php/Known_implementations of SIFT</u>



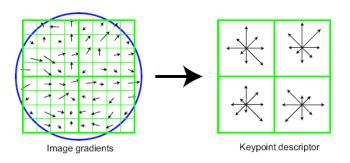


Summary

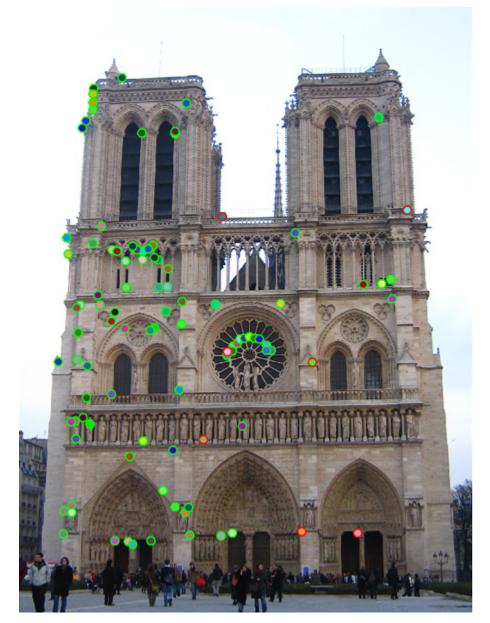
- Keypoint detection: repeatable and distinctive
 - Corners, blobs, stable regions
 - Harris, DoG

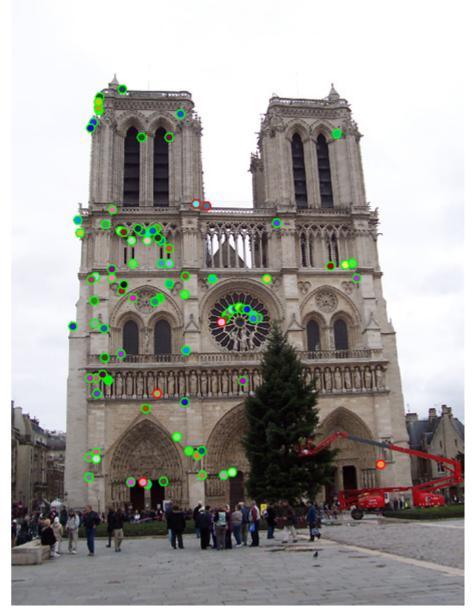


- Descriptors: robust and selective
 - spatial histograms of orientation
 - SIFT and variants are typically good for stitching and recognition
 - But, need not stick to one



Which features match?





Feature matching

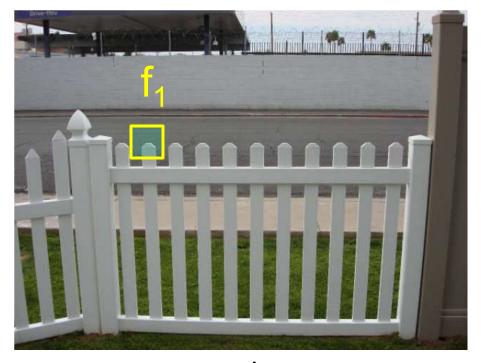
Given a feature in I_1 , how to find the best match in I_2 ?

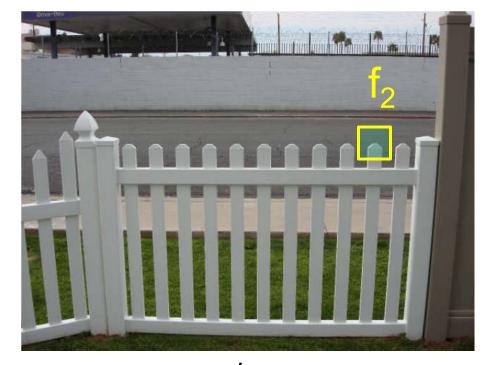
- 1. Define distance function that compares two descriptors
- 2. Test all the features in I_2 , find the one with min distance

Feature distance

How to define the difference between two features f_1 , f_2 ?

- Simple approach: L₂ distance, | |f₁ f₂ | |
- can give good scores to ambiguous (incorrect) matches



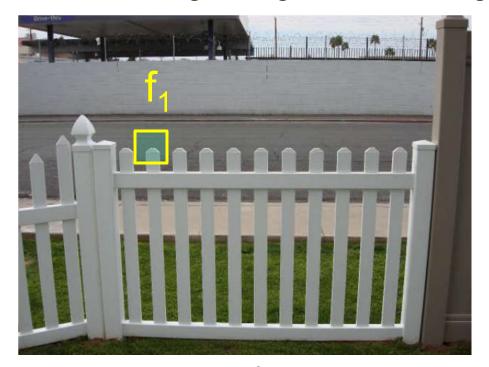


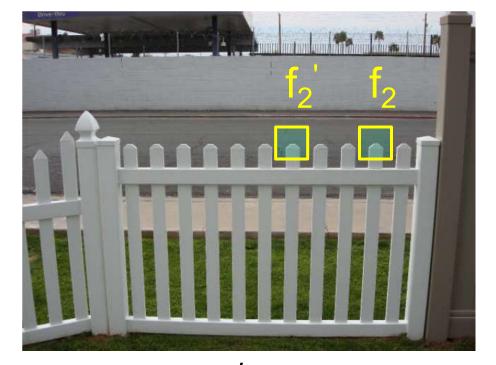
1

Feature distance

How to define the difference between two features f_1 , f_2 ?

- Better approach: ratio distance = ||f₁ f₂ || / || f₁ f₂' ||
 - f₂ is best SSD match to f₁ in l₂
 - f₂' is 2nd best SSD match to f₁ in I₂
 - gives large values for ambiguous matches





1.